

## EddyCus® TF map 2530RM – Resistivity Imaging Device

P\_T\_2530RM\_23



### Highlights

- ▶ Contact-free imaging
- ▶ High speed (10,000 points in 5 min)
- ▶ Repeatable and accurate
- ▶ High resolution (9 to 90,000 points)
- ▶ Mapping of encapsulated layers
- ▶ Homogeneity and defect imaging

### Applications

- ▶ Wafer resistivity imaging
- ▶ Ingot and boule resistivity imaging
- ▶ Sputter target composition imaging
- ▶ Purity assessment
- ▶ Electrical discharge machining
- ▶ Material sorting (map: homogeneity assessment)
- ▶ Melting, casting, sintering
- ▶ Defect imaging and integrity assessment

### Processes

- ▶ Classification and sorting
- ▶ Ingot casting and drawing (FZ, CZ)
- ▶ Implantation and doping
- ▶ Annealing and tempering
- ▶ Composition & structure assessment
- ▶ Melting, sintering, heat treatment
- ▶ EDM processability

### Materials

- ▶ Semiconductors
  - ▶ Si (mono, poly)
  - ▶ SiC, SiSiC
  - ▶ GaAs
  - ▶ GaN
- ▶ Alloys
- ▶ Metals
- ▶ Graphite
- ▶ Graphene
- ▶ Compounds
- ▶ Composites

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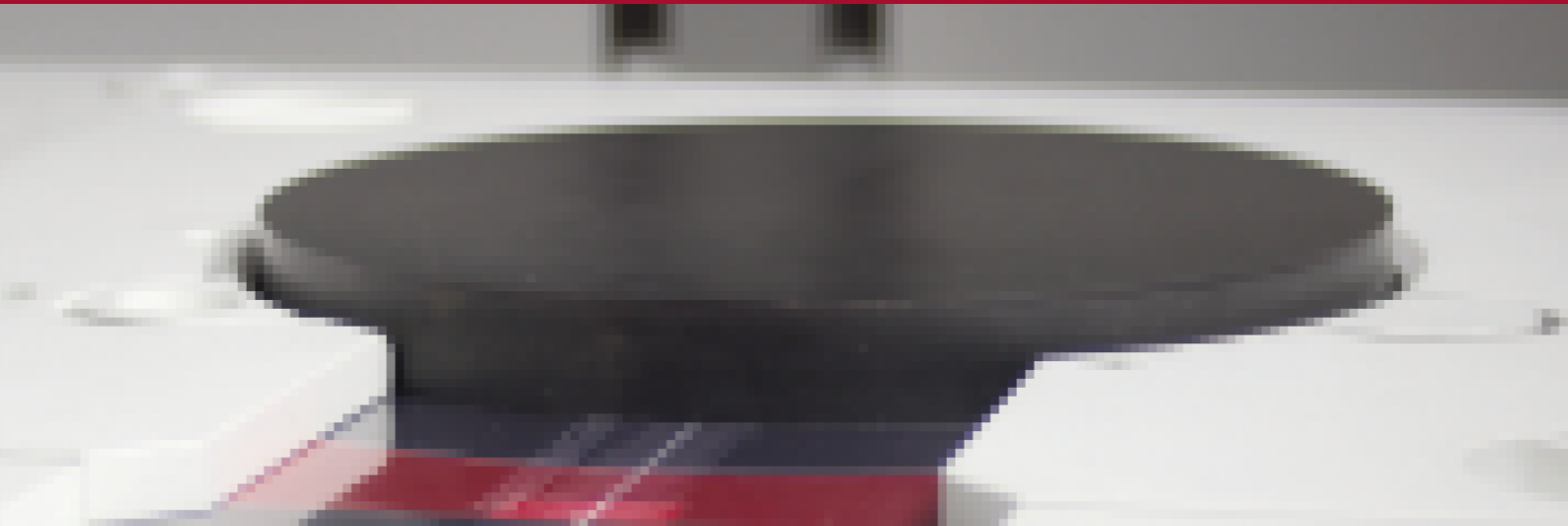
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Engineered and Made in Germany 





Measurement technology	High frequency eddy current sensor
Substrates	Flat, slightly curved
Max. scanning area	12 inch / 300 mm x 300 mm x 10 mm
Edge effect correction / exclusion	2 – 10 mm (depending on size, range, setup and requirements)
Max. sample thickness / sensor gap	10 mm
Resistivity range	0.002 – 0.1 mOhm-cm 0.1 – 100 mOhm-cm 100 – 1,000 mOhm-cm
Conductivity range	0.01 – 65 MS/m
Min. pitch	0.1 mm
Mode	Contact and non-contact
Speed	400 mm per second (time 1 to 30 minutes)
Device dimensions (w/h/d) / weight	31.5" x 19.1" x 33.5" / 785 mm x 486 mm x 850 mm / 90 kg
Further available features	Sheet resistance imaging, metal thickness imaging, anisotropy and sheet resistance sensor

## Device Control and Software

- ▶ Pre-defined measurement and product recipes (sizes, pitches, thresholds)
- ▶ Line scan, histogram and area analysis
- ▶ Black and colored image coding
- ▶ Csv & pdf export
- ▶ SPC summary and export
- ▶ 3 user levels
- ▶ Material database for parameter conversion
- ▶ Edge effect compensation
- ▶ Storage and import of data
- ▶ Export of data sets (e.g. to EddyEva, MS Excel, Origin)

